

Search Notes

Application/Control No.

10/617,532

Examiner

Tianjie Chen

Applicant(s)/Patent under
Reexamination

NAKAYAMA, MASATOSHI

Art Unit

2656

SEARCHED

| Class | Subclass | Date | Examiner |
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| Updated | | 5/3/2006 | TJ |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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